

# IRFR330B / IRFU330B

# **400V N-Channel MOSFET**

### **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

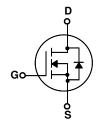
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies and electronic lamp ballasts based on half bridge.

#### **Features**

- · Low Crss (typical 20 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability







# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

| Symbol                            | Parameter   |           | IRFR330B / IRFU330B | Units |  |
|-----------------------------------|---|-----------|---------------------|-------|--|
| V <sub>DSS</sub>                  | Drain-Source Voltage  |           | 400                 | V     |  |
| I <sub>D</sub>                    | Drain Current - Continuous (T <sub>C</sub> = 25°                    | C)        | 4.5                 | Α     |  |
|                                   | - Continuous (T <sub>C</sub> = 100                                  | O°C)      | 2.9                 | Α     |  |
| I <sub>DM</sub>                   | Drain Current - Pulsed  | (Note 1)  | 18                  | Α     |  |
| V <sub>GSS</sub>                  | Gate-Source Voltage   |           | ± 30                | V     |  |
| E <sub>AS</sub>                   | Single Pulsed Avalanche Energy                                      | (Note 2)  | 330                 | mJ    |  |
| I <sub>AR</sub>                   | Avalanche Current   | (Note 1)  | 4.5                 | Α     |  |
| E <sub>AR</sub>                   | Repetitive Avalanche Energy   | (Note 1)  | 4.8                 | mJ    |  |
| dv/dt                             | Peak Diode Recovery dv/dt   | (Note 3)  | 5.5                 | V/ns  |  |
| P <sub>D</sub>                    | Power Dissipation (T <sub>A</sub> = 25°C) *                         |           | 2.5                 | W     |  |
|                                   | Power Dissipation (T <sub>C</sub> = 25°C)                           |           | 48                  | W     |  |
|                                   | - Derate above 25°C   | İ         | 0.38                | W/°C  |  |
| T <sub>J</sub> , T <sub>stg</sub> | Operating and Storage Temperature Ra                                | nge       | -55 to +150         | °C    |  |
| T <sub>L</sub>                    | Maximum lead temperature for soldering 1/8" from case for 5 seconds | purposes, | 300                 | °C    |  |

### **Thermal Characteristics**

| Symbol          | Parameter                                 | Тур | Max | Units |
|-----------------|---|-----|-----|-------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case      |     | 2.6 | °C/W  |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient * |     | 50  | °C/W  |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient   |     | 110 | °C/W  |

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

| Symbol                           | Parameter                                       | Test Conditions   |              | Min | Тур      | Max       | Units    |
|----------------------------------|---|---|--------------|-----|----------|-----------|----------|
| Off Cha                          | aracteristics                                   |   |              |     |          |           |          |
| BV <sub>DSS</sub>                | Drain-Source Breakdown Voltage                  | $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$                 |              | 400 |          |           | V        |
| $\Delta BV_{DSS}$ / $\Delta T_J$ | Breakdown Voltage Temperature<br>Coefficient    | $I_D = 250 \mu A$ , Referenced                                | to 25°C      |     | 0.4      |           | V/°C     |
| I <sub>DSS</sub>                 | Zero Osto Vallano Busin Osmanl                  | V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V                |              |     |          | 10        | μΑ       |
|                                  | Zero Gate Voltage Drain Current                 | V <sub>DS</sub> = 320 V, T <sub>C</sub> = 125°C               |              |     |          | 100       | μΑ       |
| I <sub>GSSF</sub>                | Gate-Body Leakage Current, Forward              | $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$                 |              |     |          | 100       | nA       |
| I <sub>GSSR</sub>                | Gate-Body Leakage Current, Reverse              | $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$                |              |     |          | -100      | nA       |
| On Cha                           | racteristics                                    |   |              |     |          |           |          |
| V <sub>GS(th)</sub>              | Gate Threshold Voltage                          | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$                          |              | 2.0 |          | 4.0       | V        |
| R <sub>DS(on)</sub>              | Static Drain-Source<br>On-Resistance            | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.25 A               |              |     | 0.83     | 1.0       | Ω        |
| g <sub>FS</sub>                  | Forward Transconductance                        | V <sub>DS</sub> = 40 V, I <sub>D</sub> = 2.25 A               | (Note 4)     |     | 3.9      |           | S        |
| C <sub>oss</sub>                 | Output Capacitance Reverse Transfer Capacitance | f = 1.0 MHz   |              |     | 80<br>20 | 100<br>26 | pF<br>pF |
| C <sub>iss</sub>                 | ' '   | $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$<br>f = 1.0 MHz |              |     |          |           |          |
|                                  |   |   |              |     |          |           |          |
|                                  | ing Characteristics                             | I   |              |     |          |           |          |
| t <sub>d(on)</sub>               | Turn-On Delay Time                              | $V_{DD} = 200 \text{ V}, I_{D} = 5.5 \text{ A},$              |              |     | 15       | 40        | ns       |
| t <sub>r</sub>                   | Turn-On Rise Time                               | $R_G = 25 \Omega$   |              |     | 55       | 120       | ns       |
| t <sub>d(off)</sub>              | Turn-Off Delay Time                             |   | (Note 4, 5)  |     | 85       | 180       | ns       |
| t <sub>f</sub>                   | Turn-Off Fall Time                              |   | (14010 4, 0) |     | 50       | 110       | ns       |
| Q <sub>g</sub>                   | Total Gate Charge                               | $V_{DS} = 320 \text{ V}, I_{D} = 5.5 \text{ A},$              |              |     | 25       | 33        | nC       |
| Q <sub>gs</sub>                  | Gate-Source Charge                              | V <sub>GS</sub> = 10 V  | (Note 4, 5)  |     | 4.3      |           | nC       |
| Q <sub>gd</sub>                  | Gate-Drain Charge                               |   | (14016 4, 5) |     | 11       |           | nC       |
| Drain-S                          | Source Diode Characteristics ar                 | nd Maximum Ratings  | 3            |     |          |           |          |
| I <sub>S</sub>                   | Maximum Continuous Drain-Source Did             | de Forward Current  |              |     |          | 4.5       | Α        |
| I <sub>SM</sub>                  | Maximum Pulsed Drain-Source Diode F             | orward Current  |              |     |          | 18        | Α        |
| V <sub>SD</sub>                  | Drain-Source Diode Forward Voltage              | $V_{GS} = 0 \text{ V}, I_{S} = 4.5 \text{ A}$                 |              |     |          | 1.5       | ٧        |
|                                  | <u> </u>  | V 0VI 554   |              |     | 005      | 1         |          |
| t <sub>rr</sub>                  | Reverse Recovery Time                           | $V_{GS} = 0 \text{ V}, I_{S} = 5.5 \text{ A},$                |              |     | 265      |           | ns       |

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 28.5mH, I<sub>AS</sub> = 4.5A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  5.5A, di/dt  $\leq$  300A/µs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300 $\mu$ s, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

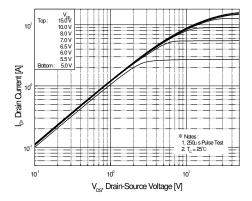


Figure 1. On-Region Characteristics

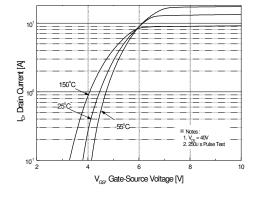


Figure 2. Transfer Characteristics

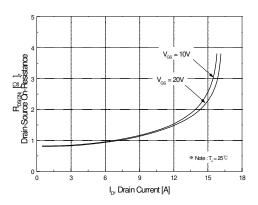


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

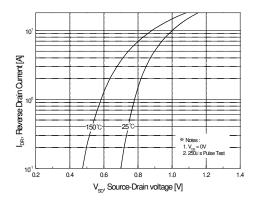


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

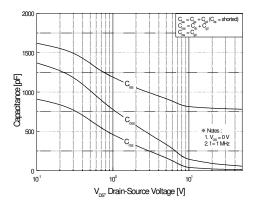


Figure 5. Capacitance Characteristics

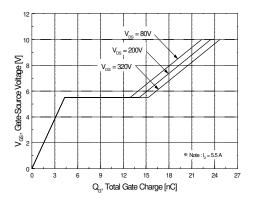


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)

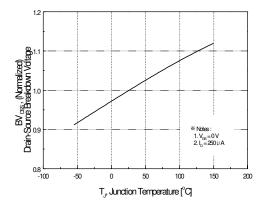


Figure 7. Breakdown Voltage Variation vs Temperature

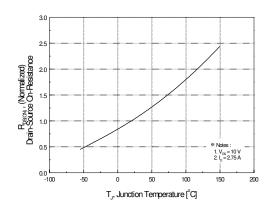


Figure 8. On-Resistance Variation vs Temperature

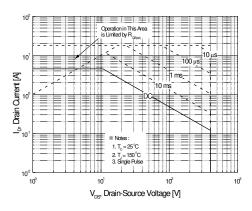


Figure 9. Maximum Safe Operating Area

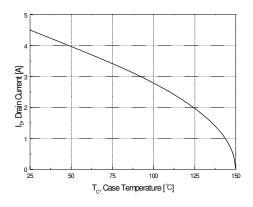


Figure 10. Maximum Drain Current vs Case Temperature

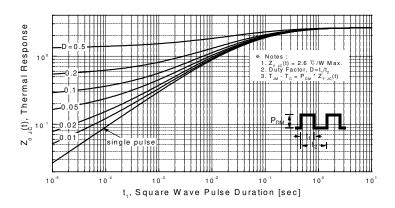
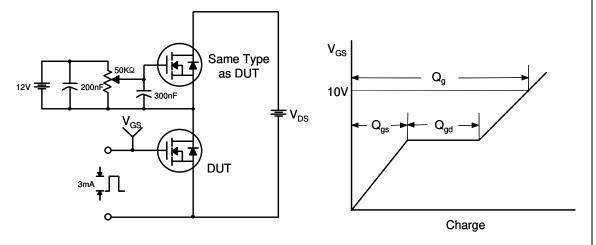


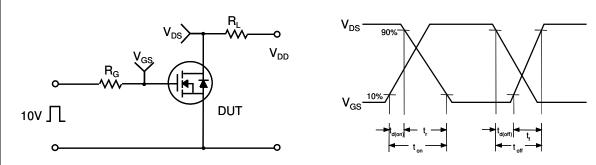
Figure 11. Transient Thermal Response Curve

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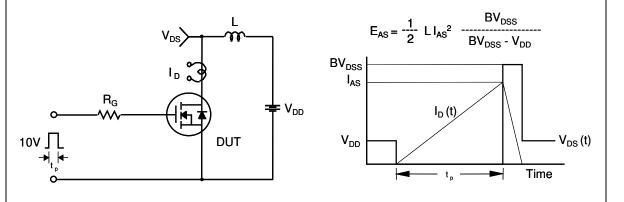
## **Gate Charge Test Circuit & Waveform**



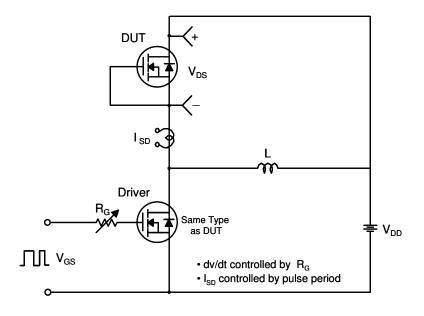
## **Resistive Switching Test Circuit & Waveforms**

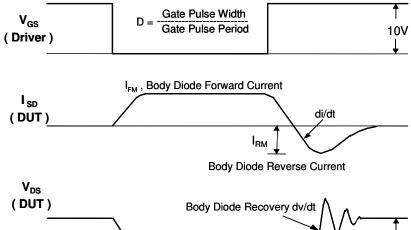


# **Unclamped Inductive Switching Test Circuit & Waveforms**



## Peak Diode Recovery dv/dt Test Circuit & Waveforms





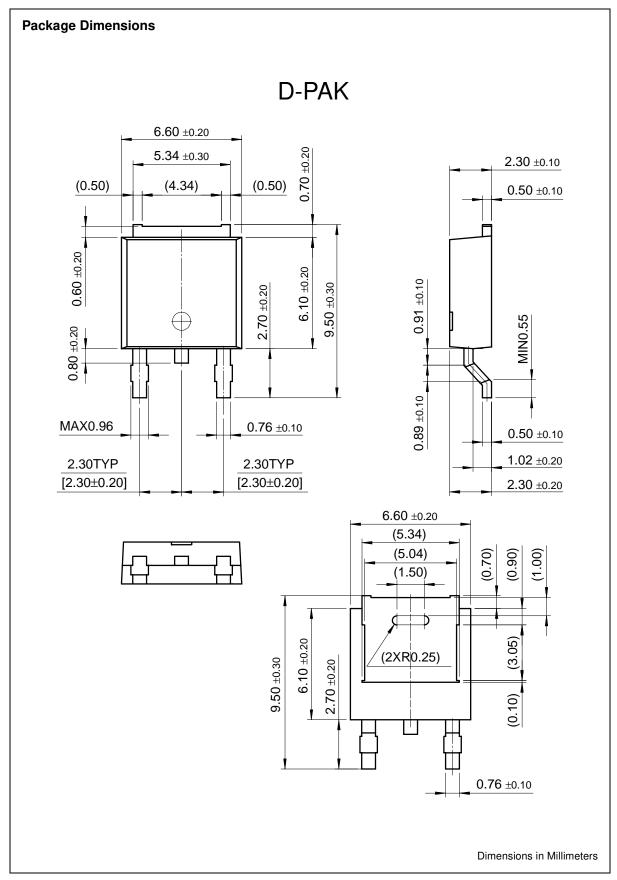
Body Diode Recovery dv/dt

V<sub>SD</sub>

Body Diode

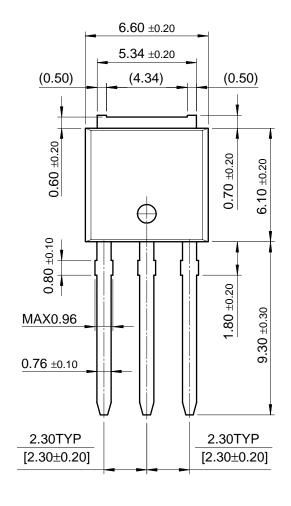
Forward Voltage Drop

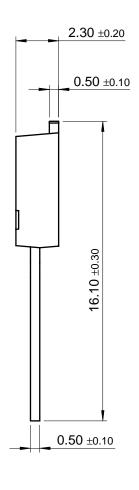
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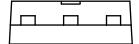




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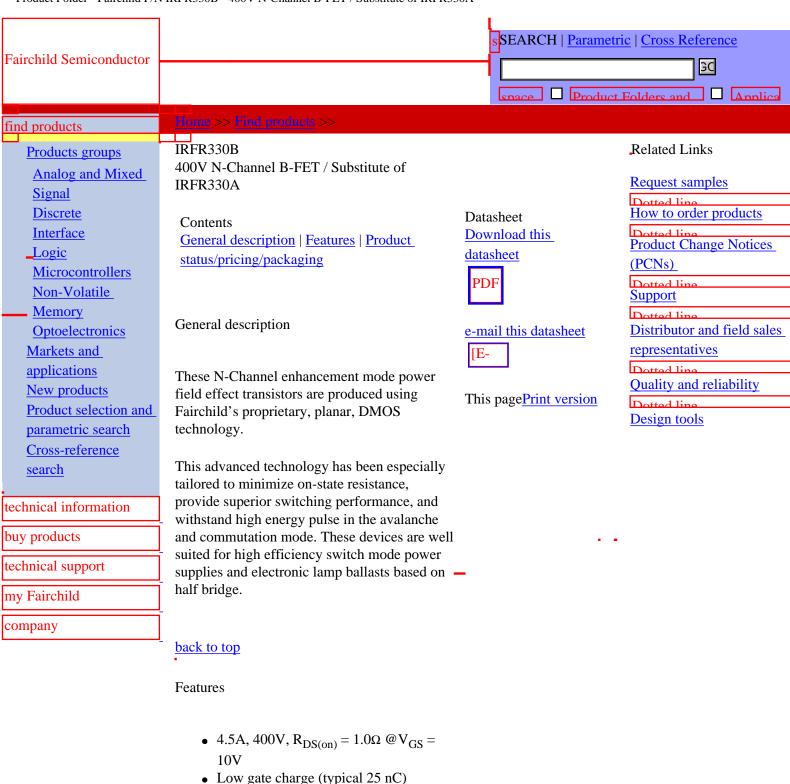
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Product status/pricing/packaging

• Low Crss (typical 20 pF)

100% avalanche testedImproved dv/dt capability

• Fast switching

| Product | Product status | Pricing* | Package type | Leads | Packing method |  |
|---------|----------------|----------|--------------|-------|----------------|--|
|         |                |          |              |       |                |  |

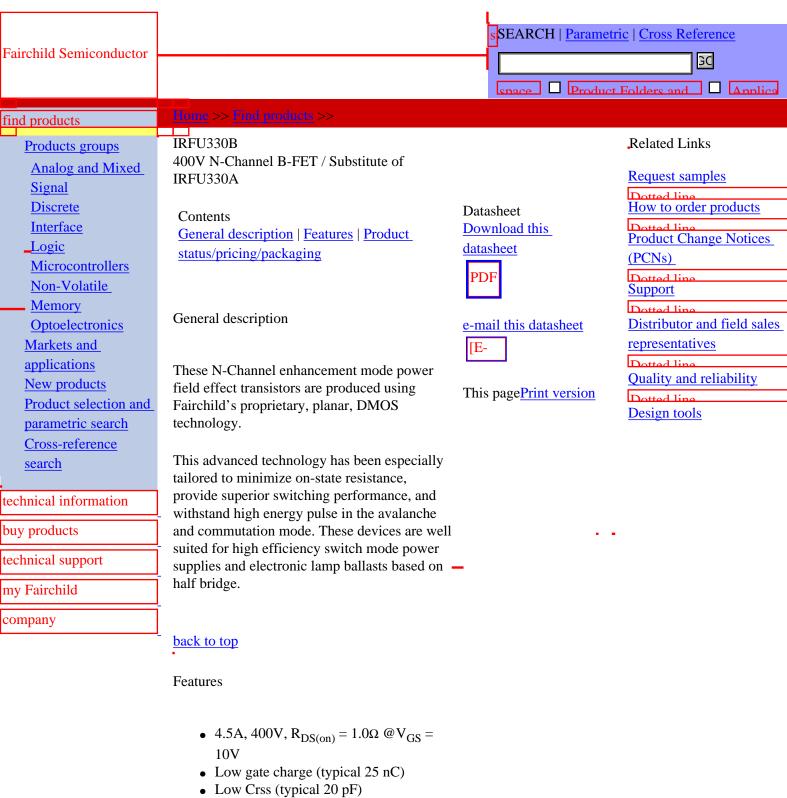
| IRFR330BTM | Full Production | \$0.62 | TO-252(DPAK) | 2 | TAPE REEL |
|------------|-----------------|--------|--------------|---|-----------|
| IRFR330BTF | Full Production | \$0.62 | TO-252(DPAK) | 2 | TAPE REEL |

<sup>\* 1,000</sup> piece Budgetary Pricing

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- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

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Product status/pricing/packaging

| Product Product status   Pricing*   Package type   Leads   Packing method |
|---|
|---|

Product Folder - Fairchild P/N IRFU330B - 400V N-Channel B-FET / Substitute of IRFU330A

| IRFU330BTU | Full Production | \$0.62 | TO-251(IPAK) | 3 | RAIL |
|------------|-----------------|--------|--------------|---|------|

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